

Special Issue

Defect Evaluation and Nondestructive Testing

Message from the Guest Editors

Defect evaluation and nondestructive testing play crucial roles in ensuring the quality, safety, and reliability of various materials and structures. As technology continues to advance, new methods and techniques are constantly emerging to improve the accuracy and efficiency of defect detection and assessment. This Special Issue aims to bring together the latest research and developments in the field of defect evaluation and nondestructive testing (NDT), promoting the exchange and development of related technologies. Recommended topics include, but are not limited to, the following:

- Innovative nondestructive testing techniques;
- Defect characterization and evaluation;
- Applications of defect evaluation and nondestructive testing;
- Data analysis and signal processing for nondestructive testing.

Keywords

- defect detection
- nondestructive testing and evaluation
- impact analysis
- defect quantification
- smart systems
- AI algorithms

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About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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